

Title (en)

Apparatus for observing a sample with a particle beam and an optical microscope

Title (de)

Vorrichtung zum Beobachten einer Probe mit einem Teilchenstrahl und einem optischen Mikroskop

Title (fr)

Appareil pour observer un échantillon avec un microscope optique et d'irradiation par particules

Publication

**EP 1953792 B1 20120516 (EN)**

Application

**EP 08150931 A 20080201**

Priority

- EP 07101725 A 20070205
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Abstract (en)

[origin: EP1953791A1] The invention relates to an apparatus for observing a sample (1) with a TEM column and a high resolution optical microscope (10). The sample position for observing the sample with the TEM column is close to the sample position for observing the sample with the optical microscope. By using an optical microscope of the scanning type, and preferably using monochromatic light, the lens elements of the optical microscope facing the sample position can be sufficiently small to be positioned between the pole faces (8A,8B) of the (magnetic) particle-optical objective lens. This is in contrast with the objective lens systems conventionally used in optical microscopes, which show a large diameter.

IPC 8 full level

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